

SEMITOP®E2

3-phase 3-Level TNPC

Engineering Sample SK25TMLID12F4TE2

Target Data

Features*

- Optimized design for superior thermal performance
- Low inductive design
- Press-Fit contact technology
- 1200V Trench IGBT4 Fast (F4)
- 650V Trench IGBT3 (E3)
- Robust and soft switching CAL4F diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

Typical Applications

- UPS
- Solar

Remarks*

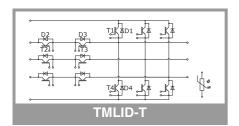
• Recommended T_{jop} = -40 ... +150°C

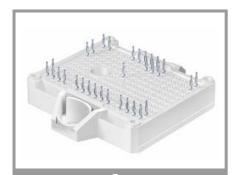
IGBT1: outer IGBTs T1 & T4IGBT2: inner IGBTs T2 & T3

• Diode1: outer Diodes D1 & D4

• Diode2: inner Diodes D2 & D3

Absolute	Maximum Rating	s		
Symbol	Conditions		Values	Unit
IGBT1		,		•
V _{CES}	T _j = 25 °C		1200	V
Ic	λ _{paste} =0.8 W/(mK)	T _s = 25 °C	34	А
	T _j = 175 °C	T _s = 70 °C	27	А
I _C	λ _{paste} =2.5 W/(mK)	T _s = 25 °C	41	Α
	T _j = 175 °C	T _s = 70 °C	33	Α
I _{Cnom}			25	Α
I _{CRM}			50	Α
V_{GES}			-20 20	V
t _{psc}	$V_{CC} = 800 \text{ V}, V_{GE} \le 15 \text{ V}, T_j = 150 \text{ °C}, V_{CES} \le 1200 \text{ V}$		6	μs
Tj			-40 175	°C
IGBT2	-			•
V _{CES}	T _i = 25 °C		650	V
Ic	λ _{paste} =0.8 W/(mK)	T _s = 25 °C	36	А
	T _j = 175 °C	T _s = 70 °C	29	Α
I _C	λ _{paste} =2.5 W/(mK)	T _s = 25 °C	42	А
	T _j = 175 °C	T _s = 70 °C	34	Α
I _{Cnom}			30	Α
I _{CRM}			50	Α
V _{GES}			-20 20	V
t _{psc}	$V_{CC} = 360 \text{ V}, V_{GE} \le 15 \text{ V}, T_j = 150 \text{ °C}, V_{CES} \le 650 \text{ V}$		6	μs
T _i	020		-40 175	°C
Diode1				I
V_{RRM}	T _i = 25 °C		1200	V
I _F	λ_{paste} =0.8 W/(mK)	T _s = 25 °C	30	А
	T _j = 175 °C	T _s = 70 °C	24	Α
l _F	λ _{paste} =2.5 W/(mK)	T _s = 25 °C	35	Α
	T _j = 175 °C	T _s = 70 °C	28	Α
I _{FRM}			50	А
I _{FSM}	10 ms, sin 180°, T _i = 25 °C		100	Α
Tj	, ,		-40 175	°C
Diode2	-			•
V _{RRM}	T _j = 25 °C		650	V
l _F	λ _{paste} =0.8 W/(mK)	T _s = 25 °C	31	Α
	T _j = 175 °C	T _s = 70 °C	24	Α
l _F	λ _{paste} =2.5 W/(mK)	T _s = 25 °C	35	Α
	T _j = 175 °C	T _s = 70 °C	28	Α
I _{FRM}		1	50	А
I _{FSM}	10 ms, sin 180°, T _j = 25 °C		180	Α
T _j			-40 175	°C
Module	•	I_		<u> </u>
I _{t(RMS)}	ΔT _{terminal} at PCB joint = 30 K, per pin		30	Α
T _{stg}	•		-40 125	°C
	1			V





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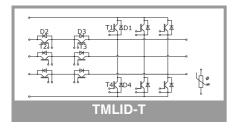
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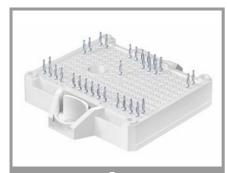
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• Diode1: outer Diodes D1 & D4

• Diode2: inner Diodes D2 & D3



Characte	ristics					
Symbol	Conditions		min.	typ.	max.	Unit
IGBT1				-71		
V _{CE(sat)}	I _C = 25 A	T _i = 25 °C		2.05	2.42	V
• CE(Sat)	V _{GE} = 15 V	T _i = 150 °C				V
	chiplevel	•		2.59	2.96	<u> </u>
V _{CE0}	chiplevel	T _j = 25 °C		1.10	1.28	V
		T _j = 150 °C		0.95	1.13	V
r _{CE}	V _{GE} = 15 V	T _j = 25 °C		38	46	mΩ
	chiplevel	T _j = 150 °C	5.0	66	73	mΩ
V _{GE(th)}	$V_{GE} = V_{CE}, I_C = 0.85 \text{ mA}$ $V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}, T_i = 25 ^{\circ}\text{C}$		5.2	5.8	6.4	V A
I _{CES}	$V_{GE} = U V, V_{CE} = 1$			1 40	1	mA
Cies	V _{CE} = 25 V	f = 1 MHz f = 1 MHz		1.43		nF nF
Coes	V _{GE} = 0 V	f = 1 MHz		t.b.d.		nF
C _{res}	V _{GE} = - 8 V+ 15 \			0.085		nC
R _{Gint}	$T_i = 25 ^{\circ}\text{C}$	1		0		Ω
	$V_{CE} = 300 \text{ V}$	T _i = 150 °C		55		ns
t _{d(on)}	I _C = 25 A	T _i = 150 °C		35		ns
E _{on}	$V_{GE} = +15/-15 \text{ V}$	T _i = 150 °C		0.85		mJ
t _{d(off)}	$R_{G \text{ on}} = 20 \Omega$	T _j = 150 °C		240		ns
t _f	$R_{G \text{ off}} = 20 \Omega$	T _i = 150 °C		50		ns
4		1,-100 0				1.0
E _{off}		T _j = 150 °C		0.9		mJ
R _{th(j-s)}	per IGBT, λ _{paste} =0.	8 W/(mK)		1.17		K/W
R _{th(j-s)}	per IGBT, λ _{paste} =2.	5 W/(mK)		0.85		K/W
IGBT2						
V _{CE(sat)}	I _C = 25 A	T _j = 25 °C		1.36	1.725	V
	V _{GE} = 15 V chiplevel	T _j = 150 °C		1.55	1.90	V
V _{CE0}		T _i = 25 °C		0.90	1.00	V
	chiplevel	T _i = 150 °C		0.82	0.90	V
r _{CE}	V _{GE} = 15 V	T _i = 25 °C		18	29	mΩ
	chiplevel	T _i = 150 °C		29	40	mΩ
V _{GE(th)}	$V_{GE} = V_{CE}, I_{C} = 0.4$	3 mA	5.1	5.8	6.4	V
I _{CES}	$V_{GE} = 0 \text{ V}, V_{CE} = 68$	50 V, T _j = 25 °C			1	mA
C _{ies}	V 05.V	f = 1 MHz		1.63		nF
Coes	$V_{CE} = 25 \text{ V}$ $V_{GE} = 0 \text{ V}$	f = 1 MHz		0.108		nF
C _{res}	VGE = U V	f = 1 MHz		0.05		nF
Q_{G}	V _{GE} = - 8 V+ 15 \	<i>i</i>		240		nC
R _{Gint}	T _j = 25 °C			0		Ω
t _{d(on)}	$V_{CE} = 300 \text{ V}$	T _j = 150 °C		35		ns
t _r	$I_C = 25 \text{ A}$	T _j = 150 °C		13		ns
Eon	$V_{GE} = +15/-15 \text{ V}$ $R_{G \text{ on}} = 15 \Omega$ $R_{G \text{ off}} = 15 \Omega$	T _j = 150 °C		0.39		mJ
t _{d(off)}		T _j = 150 °C		390		ns
t _f		T _j = 150 °C		75		ns
E _{off}		T _j = 150 °C		0.91		mJ
R _{th(j-s)}	per IGBT, λ _{paste} =0.8 W/(mK)			1.73		K/W
R _{th(j-s)}	per IGBT, λ _{paste} =2.			1.36		K/W



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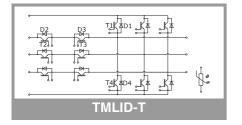
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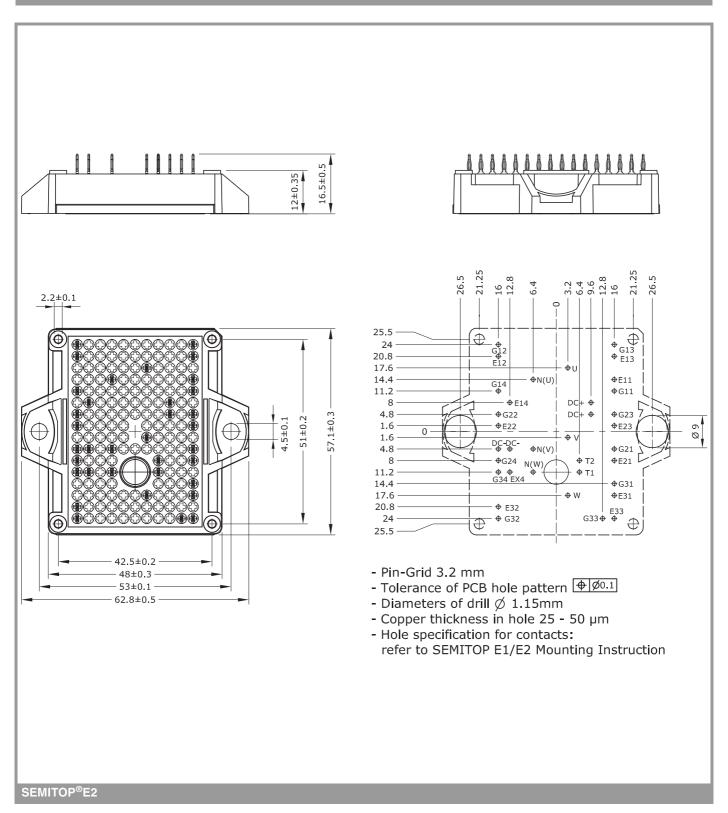
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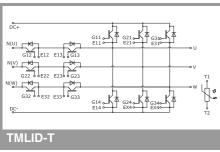
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IGBT2: inner IGBTs T2 & T3
Diode1: outer Diodes D1 & D4

• Diode2: inner Diodes D2 & D3

Characte	eristics					
Symbol	Conditions		min.	typ.	max.	Unit
Diode1						•
$V_F = V_{EC}$	I _F = 25 A	T _j = 25 °C		2.41	2.74	V
	chiplevel	T _j = 150 °C		2.45	2.79	V
V_{F0}		T _i = 25 °C		1.30	1.50	V
	chiplevel	T _i = 150 °C		0.90	1.10	V
r _F	chiplevel	T _j = 25 °C		44	50	mΩ
		T _j = 150 °C		62	68	mΩ
I _{RRM}	I _F = 25 A	T _j = 150 °C		t.b.d.		Α
Q _{rr}	V _R = 300 V	T _j = 150 °C		t.b.d.		μC
E _{rr}	$V_{GE} = +15/-15 \text{ V}$	T _j = 150 °C		0.75		mJ
R _{th(j-s)}	per Diode, λ _{paste} =0.8 W/(mK)			1.66		K/W
R _{th(j-s)}	per Diode, λ _{paste} =2.5 W/(mK)			1.29		K/W
Diode2	•					•
$V_F = V_{EC}$	I _F = 25 A	T _j = 25 °C		1.50	1.92	V
	chiplevel	T _j = 150 °C		1.55	2.01	V
V _{F0}		T _i = 25 °C		1.04	1.24	V
	chiplevel	T _j = 150 °C		0.85	0.99	V
r _F	1	T _j = 25 °C		19	27	mΩ
	chiplevel	T _j = 150 °C		28	41	mΩ
I _{RRM}	I _F = 25 A	T _j = 150 °C		t.b.d.		Α
Q _{rr}	V _R = 300 V	T _j = 150 °C		t.b.d.		μС
E _{rr}	$V_{GE} = +15/-15 \text{ V}$	T _j = 150 °C		0.21		mJ
R _{th(j-s)}	per Diode, λ _{paste} =0.8 W/(mK)			2.27		K/W
R _{th(j-s)}	per Diode, λ _{paste} =2.5 W/(mK)			1.88		K/W
Module	·					1
L _{sCE1}				t.b.d.		nH
L _{CE}				t.b.d.		nH
R _{CC'+EE'}		T _s = 25 °C		-		mΩ
		T _s = 150 °C		-		mΩ
Ms	to heatsink	ı	1.6		2.3	Nm
M _t				-		Nm
						Nm
W				35		g
Tempera	ture Sensor					
R ₁₀₀	T _c =100°C (R ₂₅ =5 kΩ)			493 ± 5%		Ω
B _{100/125}	$R_{(T)}=R_{100}exp[B_{100/125}(1/T-1/T_{100})]; T[K];$			3550 ±2%		К







This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

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